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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/448,756	11/24/1999	JUN KOYMA	0756-2070	5419

22204 7590 06/25/2004

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EXAMINER

BELL, PAUL A

ART UNIT PAPER NUMBER

2675

DATE MAILED: 06/25/2004

28

Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary

Application No.

09/448,756

Applicant(s)

KOYMA ET AL.

Examiner

PAUL A BELL

Art Unit

2675

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --
Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM
THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 07 April 2004.
2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-9, 11-27 and 29-38 is/are pending in the application.
4a) Of the above claim(s) _____ is/are withdrawn from consideration.
5) ☐ Claim(s) _____ is/are allowed.
6) ☒ Claim(s) 1-9, 11-27 and 29-38 is/are rejected.
7) ☐ Claim(s) _____ is/are objected to.
8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
10) ☐ The drawing(s) filed on _____ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
a) ☒ All b) ☐ Some * c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
2. ☒ Certified copies of the priority documents have been received in Application No. 08/803,217.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- 1) ☐ Notice of References Cited (PTO-892)
2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3) ☒ Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)
Paper No(s)/Mail Date 25.
4) ☐ Interview Summary (PTO-413)
Paper No(s)/Mail Date. _____.
5) ☐ Notice of Informal Patent Application (PTO-152)
6) ☐ Other: _____.

DETAILED ACTION

1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

2. Claim 1-9, 11-27 and 29-38 are rejected under 35 U.S.C. 103(a) as being unpatentable over Matsumoto (5,323,042) in view of Adachi et al. (5,631,664) and Stewart (5,302,966).

With regard to claim 1 Matsumoto teaches an active matrix type display device comprising: a substrate having an insulating surface , a plurality of pixel electrodes arranged in a matrix form over said substrate , a plurality of switching elements operationally connected to said pixel electrodes, each of said switching elements comprising a thin film transistor (column 1, lines 5-12 figure 1, item 12, figure 4, item 6); and a driver circuit comprising a plurality of thin film transistors for driving said plurality of switching elements (figure 1, item 13, figure 4, item 2 and 3), wherein each of said plurality of thin film transistors comprises a crystallized semiconductor layer (column 3, lines 59-64), a gate insulating film adjacent to said crystallized semiconductor layer and a gate electrode adjacent to said gate insulating film (figure 1, items 26, 24, and 22).

Matsumoto does not teach " a display medium comprising an emissive material and capable of electrically changing luminous strength disposed at each of said pixel electrodes" . Matsumoto instead teaches a display medium being an liquid crystal which is not an "emissive material".

Adachi et al. teaches a preference for EL or electroluminescence material which is a "emissive material" over liquid crystal material (See Adachi et al. column 1, lines 37-66). Stewart teaches with regards to using EL or LCD material in a matrix that, "Recently active matrix technology known in the liquid crystal display art has been applied to EL displays", (SEE Stewart column 1, lines 19-21).

Therefore it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify the Matsumoto display medium to be EL instead of LC because Adachi et al. provided the suggestion and motivation to substitute EL for LC (See Adachi et al. column 1, lines 37-66) and still further Stewart provided the "reasonable expectation of success" in making the change (SEE Stewart column 1, lines 19-21).

With regard to claim 2 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said gate electrode is located over said semiconductor layer (See Matsumoto figure 1, items 26 and 11).

With regards to claim 3 Matsumoto as modified by Adachi et al. and Stewart teaches wherein all of said plurality of thin film transistors are p-type (See Matsumoto column 5, line 6768).

With regard to claim 4 Matsumoto as modified by Adachi et al. and Stewart teaches wherein all of said plurality of thin film transistors are n-type (See Matsumoto column 5, line 6768).

With regard to claim 5 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said substrate is a glass substrate (See Matsumoto column 3, line 3).

With regard to claim 6 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said crystallized semiconductor layer comprises silicon (See Matsumoto column 3, line 60).

With regard to claim 7 Matsumoto as modified by Adachi et al. and Stewart teaches an active matrix type display device comprising: a substrate having an insulating surface, a plurality of pixel electrodes arranged in a matrix form over said substrate, a plurality of switching elements operationally connected to said pixel electrodes, each of said switching elements comprising a thin film transistor (See Matsumoto column 1, lines 5-12 figure 1, item 12, figure 4, items 6 and 7), and a driver circuit comprising a plurality of thin film transistors for driving said plurality of switching elements (See Matsumoto figure 1, item 13, figure 4, item 2 and 3), wherein each of said plurality of thin film transistors comprises a crystallized semiconductor layer (See Matsumoto column 3, lines 59-64), a gate insulating film adjacent to said crystallized semiconductor layer and a gate electrode adjacent to said gate insulating film (See Matsumoto figure 1, items 26, 24, and 22) , wherein said crystallized semiconductor layer has source and drain regions and at least one lightly doped region (See Matsumoto column 3, lines 7-17).

With regard to claim 8 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said substrate is a glass substrate (See Matsumoto column 3, line 3).

With regard to claim 9 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said source and drain regions and said at least one lightly doped region are doped with phosphorus (See Matsumoto column 4, lines 1-35).

With regard to claim 11 Matsumoto teaches as modified by Adachi et al. and Stewart wherein said gate electrode is located over said semiconductor layer (See Matsumoto figure 1, items 26 and 11) .

With regard to claim 12 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said crystallized semiconductor layer comprises silicon (See Matsumoto column 3, line 60).

With regard to claim 13 Matsumoto as :modified by Adachi et al. and Stewart teaches an active matrix type display device comprising: a substrate having an insulating surface; a plurality of pixel electrodes arranged in a matrix form over said substrate; a plurality of switching elements operationally connected to said pixel electrodes (See Matsumoto column 1, lines 5-12 figure 1, item 12, figure 4, item 7), each of said switching elements comprising a thin film transistor (See Matsumoto figure 1, item 12:, figure 4, item 6), and a CMOS circuit comprising at least one n-channel type thin film transistor and one p-channel type thin film transistor (See Matsumoto column 2, line 68), wherein each of said n-channel and p-channel type thin film transistors comprises a crystallized semiconductor layer (See Matsumoto column 3, lines 59-64), a gate insulating film adjacent to said crystallized semiconductor layer and a gate electrode adjacent to said gate insulating film (See Matsumoto figure 1, items 26, 24, and 22).

With regard to claim 14 Matsumoto as modified by Adachi et al. and Stewart teaches wherein aid substrate is a glass substrate (See Matsumoto column 3, line 3).

With regard to claim 15 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said gate electrode is located over said semiconductor layer (See Matsumoto figure 1, items 26 and 11) .

With regard to claim 16 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said crystallized semiconductor layer comprises silicon (See Matsumoto column 3, line 60).

With regard to claim 17 Matsumoto as modified by Adachi et al. and Stewart teaches an active matrix type display device comprising: a substrate having an insulating surface, a plurality of pixel electrodes arranged in a matrix form over said substrate, a plurality of switching elements operationally connected to said pixel electrodes (See Matsumoto column 1, lines 5-12 figure 1, item 12, figure 4, item 6), each of said switching elements comprising a thin film transistor (See Matsumoto figure 1, item 12, figure 4, item 6), and a CMOS circuit comprising at least one n-channel type thin film transistor and one p-channel type thin film transistor (See Matsumoto column 2, line 68), each of said thin. film transistors comprising a crystallized semiconductor layer (See Matsumoto column 3, lines 59-64), a gate insulating film adjacent to said crystallized semiconductor layer and a gate electrode adjacent to said gate insulating film (See Matsumoto figure 1, items 26, 24, and 22), wherein said crystallized semiconductor layer has source and drain regions and at least one lightly doped region (See Matsumoto column 3, lines 7-17).

With regard to claim 18 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said substrate is a glass substrate (See Matsumoto column 3, line 3).

With regard to claim 19 Matsumoto teaches as modified by Adachi et al. and Stewart an active matrix type display device comprising: a substrate having an insulating surface, a plurality of pixel electrodes arranged in a matrix form over said substrate, a plurality of switching elements operationally connected to said pixel electrodes (See Matsumoto column 1, lines 5-12 figure 1, item 12, figure 4, item 6), each of said switching elements comprising a thin film transistor (See Matsumoto figure 1, item 12, figure 4, item 7), and a driver circuit comprising a plurality of thin film transistors for driving said plurality of switching elements (See Matsumoto figure 4, items 2 and 3), wherein each of the film transistors of said switching elements and said driver circuit comprises a crystallized semiconductor layer (See Matsumoto column 3, lines 5964), a gate insulating film adjacent to said crystallized semiconductor layer and a gate electrode adjacent to said gate insulating film (See Matsumoto figure 1, items 26, 24, and 22).

With regard to claim 20 Matsumoto as :modified by Adachi et al. and Stewart teaches wherein said gate electrode is located over said semiconductor layer (See Matsumoto figure 1, items 26 and 11) .

With regard to claim 21 Matsumoto as modified by Adachi et al. and Stewart teaches wherein all of said plurality of thin film transistors are p-type (See Matsumoto column 5, line 6768).

With regard to claim 22 Matsumoto as modified by Adachi et al. and Stewart teaches wherein all of said plurality of thin film transistors are n-type (See Matsumoto column 5, line 6768).

With regard to claim 23 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said substrate is a glass substrate (See Matsumoto column 3, line 3).

With regard to claim 24 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said crystallized semiconductor layer comprises silicon (See Matsumoto column 3, line 60).

With regard to claim 25 Matsumoto as modified by Adachi et al. and Stewart teaches In regards to claim 25 An active matrix type display device comprising: a substrate having an insulating surface, a plurality of pixel electrodes arranged in a matrix form over said substrate, a plurality of switching elements operationally connected to said pixel electrodes (See Matsumoto column 1, lines 5-12 figure 1, item 12, figure 4, item 6), each of said switching elements comprising a thin film transistor (See Matsumoto figure 1, item 12, figure 4, item 7), and a driver circuit comprising a plurality of thin film transistors for driving said plurality of switching elements (See Matsumoto figure 4, items 2 and 3), wherein each of the thin film transistors of the switching elements and the driver circuit comprises a crystallized semiconductor layer (See Matsumoto column 3, lines 59-64), a gate insulating film adjacent to said crystallized semiconductor layer, and a gate electrode adjacent to said gate insulating film (See Matsumoto figure 1, items 26, 24, and 22), wherein said crystallized semiconductor layer has source and drain regions and at least one lightly doped region (See Matsumoto column 3, lines 7-17).

With regard to claim 26 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said substrate is a glass substrate (See Matsumoto column 3, line 3).

With regard to claim 27 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said source and drain regions and said at least one lightly doped region are doped with phosphorus (See Matsumoto column 4, lines 1-35).

With regard to claim 29 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said gate electrode is located over said semiconductor layer (See Matsumoto figure 1, items 26 and 11) .

With regard to claim 30 Matsumoto as modified by Adachi et al. and Stewart teaches In regards to claim 30 wherein said crystallized semiconductor layer comprises silicon (See Matsumoto column 3, line 60).

With regard to claim 31 Matsumoto as modified by Adachi et al. and Stewart teaches an active matrix type display device comprising: a substrate having an insulating surface, a plurality of pixel electrodes arranged in a matrix form over said substrate, a plurality of switching elements operationally connected to said pixel electrodes (See Matsumoto column 1, lines 5-12 figure 1, item 12, figure 4, item 6), each of said switching elements comprising a thin film transistor (See Matsumoto figure 1, item 12, figure 4, item 7), and a CMOS circuit comprising at least one n-channel type thin film transistor and one p-channel type thin film transistor (See Matsumoto column 2, line 68), wherein each of the film transistors of the switching elements and said n-channel and p-channel type thin film transistors comprises a crystallized semiconductor layer (See Matsumoto column 3, lines 59-64), a gate insulating film adjacent to said crystallized semiconductor layer and a gate electrode adjacent to said gate insulating film See Matsumoto figure 1, items 26, 24, and 22).

With regard to claim 32 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said substrate is a glass substrate (See Matsumoto column 3, line 3).

With regard to claim 33 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said gate electrode is located over said semiconductor layer (figure 1, items 26 and 11) .

With regard to claim 34 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said crystallized semiconductor layer comprises silicon (See Matsumoto column 3, line 60).

With regard to claim 35 Matsumoto as modified by Adachi et al. and Stewart teaches an active matrix type display device comprising: a substrate having an insulating surface, a plurality of pixel electrodes arranged in a matrix form over said substrate, a plurality of switching elements operationally connected to said pixel electrodes (See Matsumoto column 1, lines 5-12 figure 1, item 12, figure 4, item 6), each of said switching elements comprising a thin film transistor (See Matsumoto figure 1, item 12, figure 4, item 7), and a CMOS circuit comprising at least one n-channel type thin film transistor and one p-channel type thin film transistor (See Matsumoto column 2, line 68), wherein each of the film transistors of the switching elements and said n-channel and p-channel type thin film transistors comprises a crystallized semiconductor layer (See Matsumoto column 3, lines 59-64), a gate insulating film adjacent to said crystallized semiconductor layer and a gate electrode adjacent to said gate insulating film (See Matsumoto figure 1, items 26, 24, and 22), and said crystallized

semiconductor layer has source and drain regions and at least one lightly doped region
(See Matsumoto column 3, lines 7-17).

With regard to claim 36 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said substrate is a glass substrate (See Matsumoto column 3, line 3).

With regard to claim 37 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said crystallized semiconductor layer comprises silicon (See Matsumoto column 3, line 60).

With regard to claim 38 Matsumoto as modified by Adachi et al. and Stewart teaches wherein said crystallized semiconductor layer comprises silicon (See Matsumoto column 3, line 60).

3. Applicant's arguments with respect to claim 1 have been considered but are moot in view of the new ground(s) of rejection.

Conclusion

4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Paul Bell whose telephone number is (703) 306-3019.


If attempts to reach the examiner by telephone are unsuccessful the Technology Center 2600 Customer Service Office whose telephone number is (703) 306-0377 can help with any inquiry of a general nature or relating to the status of this application.

Any response to this action should be mailed to:

Commissioner of Patents and Trademarks
Washington, D.C. 20231

Or Faxed to: (703) 872-9306

Or Hand-delivered to: Crystal Park II, 2121 Crystal Drive, Arlington, VA, Sixth Floor
(Receptionist)


Paul Bell
Art unit 2675
June 18, 2004


CHANH NGUYEN
PRIMARY EXAMINER